

Cold Electronics Review

Wednesday, 12 October 2016

Plenary: Session 2 - Large Conference Room (13:30 - 17:00)

time	[id] title	presenter
13:30	[41] Front-End and ADC ASIC Design	Dr LI, Shaorui
14:30	[43] FE and ADC ASIC Testing Summary	Dr GAO, Shanshan
15:00	Coffee Break	
15:20	[44] Lessons Learned from MicroBooNE/35-ton	Dr RADEKA, Veljko
16:00	[45] Plans for ProtoDUNE/SBND Integrated System Testing	WORCESTER, Matthew SHAW, Theresa
16:30	[61] Joint Discussion	

Thursday, 13 October 2016

Plenary: Session 3 - Large Conference Room (14:00 - 17:00)

time	[id] title	presenter
14:00	[53] Cold Electronics Risks & Plans for Risk Mitigation	WORCESTER, Matthew
14:30	[54] Potential Catastrophic Failure Modes & System Protections	Dr RADEKA, Veljko
15:00	Coffee Break	
15:15	[55] Cold Electronics QA/QC Plan	SHOOLTZ, Dean
15:45	[56] SBND/ProtoDUNE Schedule	WORCESTER, Matthew
16:15	[57] Tour of Electronics Lab - Group 2	Dr CHEN, Hucheng Dr GAO, Shanshan